

NASA Physics of Failure (PoF) Handbook Update

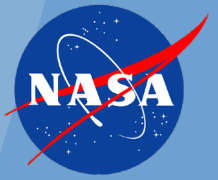
June 3, 2024

Nancy J. Lindsey, 370 Staff Engineer (GSFC RMA SME)

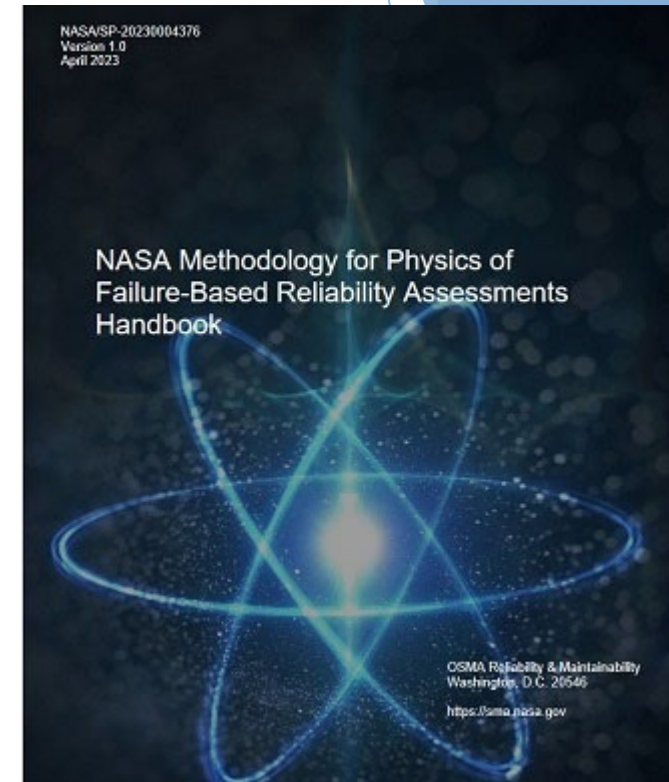
For the PoF Handbook Development Team: Jeff Dawson (GSFC), Nobel Sindjui (GSFC), Doug Sheldon (JPL), Nancy Lindsey (HQ/GSFC), Anthony DiVenti (NASA R&M Technical Fellow), and many contributing authors



Outline

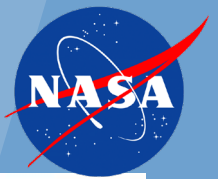


- Why Physics of Failure ?
- Physics of Failure (PoF) Handbook (NASA/SP-20230004376)
- PoF Use & Examples
- How can the Community Contribute?
- Questions



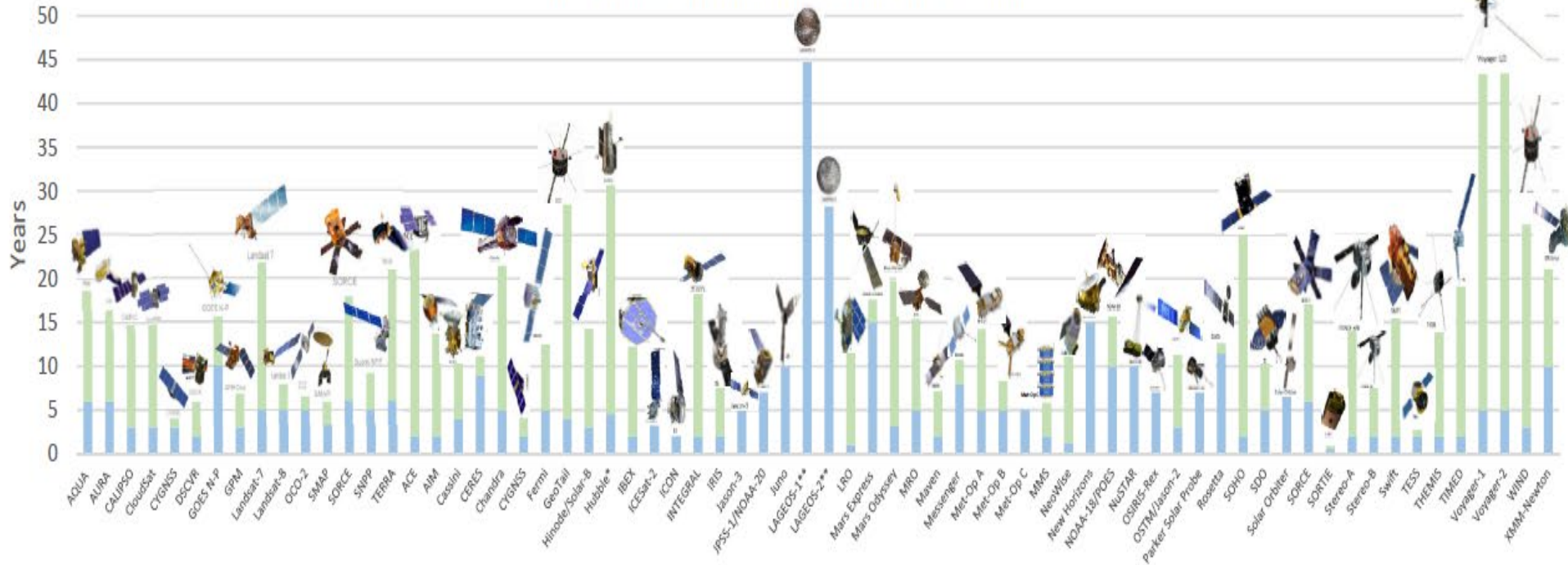
<https://ntrs.nasa.gov/citations/20230004376>

Why Physics of Failure (PoF)?

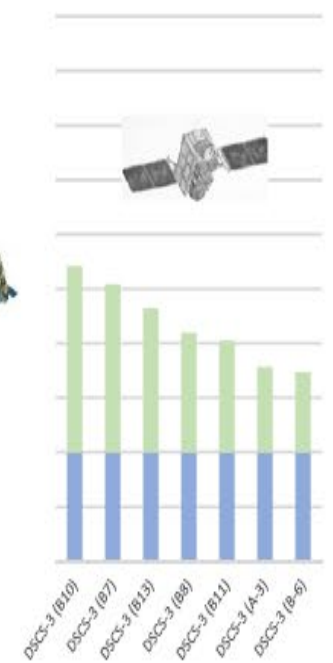


Currently Operating Spacecraft

Free Flyer NASA Mission Life versus Design Goal



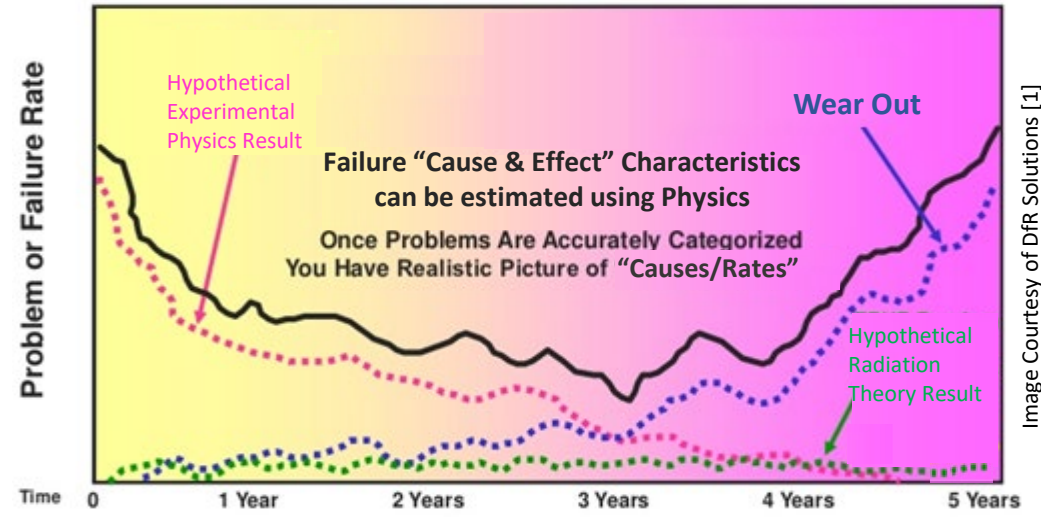
Defense Mission Life versus Design Goal



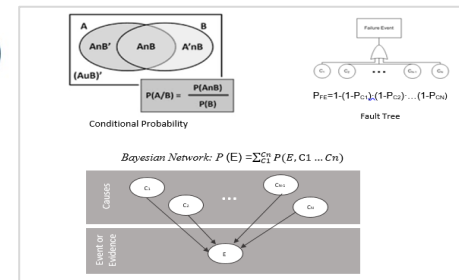
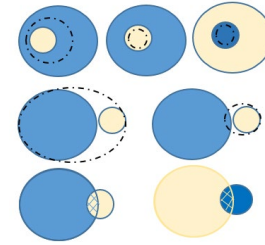
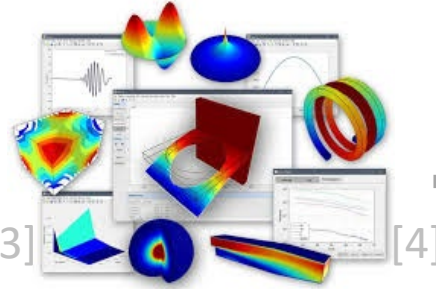
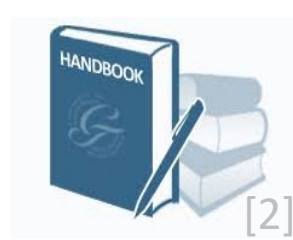
Unrealistically conservative estimations of life are being assumed based on our highly conservative predictions.

Why Physics of Failure (PoF)?

Transition from bathtub curve assumptions to Root Cause Models for more realistic risk assessments.



All
 $\sum_{L=1}$

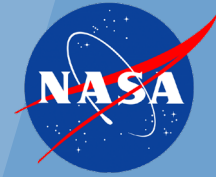


(..... Data/Models.....)

(..... Likelihood Relationships and Statistical Fusion Processes.....)

NASA Physics of Failure (PoF) Handbook

NASA/SP-20230004376



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Empirical: Analysis methods that study the failure history of parts under given conditions, then fits the failure data to a probability distribution. Responsive to new concepts.

Deterministic: Analysis methods that involve the study of the predicted underlying physical processes/causes that could cause failure and results in a mathematical relationship describing the failure potential. Responsive to new concepts.

Aggregation: Using a single method or multiple methods concurrently with or in lieu of reference rates (e.g., handbook data) to develop system failure likelihood using statistical techniques and considering dependencies of individual findings. . Responsive to capability/concept advancement uncertainties, model-based, etc.

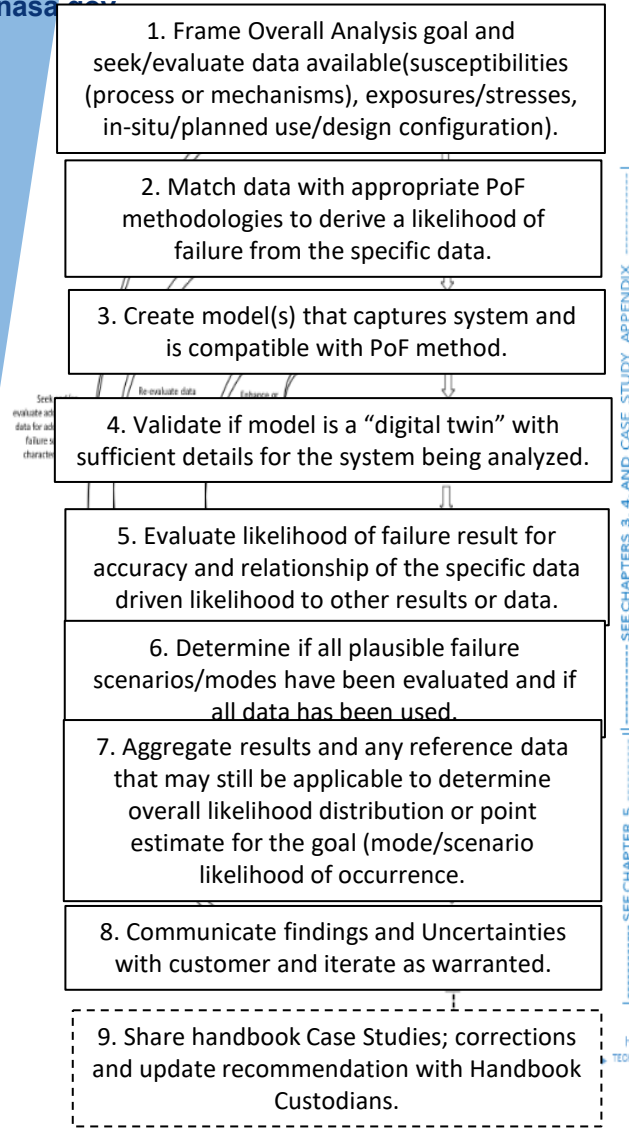
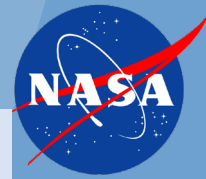
Future: Technology advancement infusion of Multiphysics tools, Artificial Intelligence, and Machine Learning.

Case Studies: NASA examples of application (separate and controllable); Ever increasing set – Community sourcing!



Share and Advance!





Mission Use Case

- 1) Estimate failure probability of Payload with history on similar missions of 7,127,352 hrs and no failures
- 2) Estimate failure probability a structural failure mode in a PWB/ PWB part on a Sounding Rocket or life with planned stress exposure
- 3) A mission system is planning to use a proven and well-known terrestrial component ($P_s = 0.8$ at the mission duration) in a space application, and it has been determined via radiation susceptibility testing, that the probability of failure from radiation, P_f , equals 0.7. What is the full P_f ?

Approach/Result

1) Bayes' estimation

$$\delta = \frac{1}{[CoV(\lambda)]^2} = 4$$

$$E(\lambda) = 1.33 \times 10^{-6} [Parts \text{ Count Failure Rate}]$$

$$\rho = \frac{\delta}{E(\lambda)} = 3.01 \times 10^6 \text{ hours}$$

$T = 7,127,352 \text{ hrs}$ and the number of failures $r = 0$

$$\lambda_{Bayesian} = \frac{\delta'}{\rho'} = \frac{\delta+r}{\rho+T} = 3.95 \times 10^{-7} \left(\frac{1}{\text{hours}} \right)$$

2) Fatigue Analysis estimation

Board: disconnect/failure in 1.71E3 hours

Site ID	Failure Mode	Damage Ratio
RL1	interconnect-open	5.85E-01
RL3	interconnect-open	4.68E-01
LS1	interconnect-open	2.69E-01
LS3	interconnect-open	2.60E-01
D4	solder-open	7.06E-02
D2	solder-open	3.92E-02
J762	interconnect-open	1.86E-02
LS2	interconnect-open	1.74E-02
J763	interconnect-open	1.49E-02
D6	solder-open	1.42E-02

Part hours to failure 6.62E1

Part Id:	U9
Condition Name:	stress_1
Condition Number:	1
Damage Ratio:	15.114873
Damage:	1.511487e+001
Applied Time:	1000.000000 hrs
Days to failure:	2.76E0
Hrs to failure:	6.62E1
Max. PSD:	0.020543

3) Assuming that the terrestrial and radiation failure mechanisms are independent or disjointed, and would use a fault tree or a Bayesian network to find P_f :

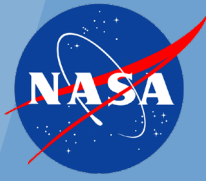
$$(1-P_{ST}) + P_{fR} - P_{fTANDR} = 0.2 + 0.7 - (0.7*0.2) = 0.76$$

$$\Sigma (P(F|T, R) = (P(F|R)*P_{fR} * (1-P_{fT}) + (P(F|T) * P_{fT} * (1-P_{fR})) + (P(F|R,T)) * (P_{fR} * P_{fT}) * (1-P_{fOther}))$$

$$\Sigma (P(F|T, R) = 1*0.7*0.8 + 1*0.2*0.3 + (1*(0.7*0.2)*1) = 0.76$$



Community Engagement for R&M Physics of Failure (PoF) Handbook Advancement/Continued Evolution



Use PoF Methods in Mission Work

Reliability, Maintainability, and Availability Knowledge Portal

- 1. Introduction
- 2. Policies, Standards and Requirements Guidance
- 3. RMA Application Rationale
- 4. R&M Guidance and Reference Data
- 5. Specialty Topics

Specialty Topics

This section addresses higher level topics/questions/problems/investigations or "Special Topics" in the RMA Engineering discipline that could impact, inform, or advance the community as a whole. Although these larger scale topics come up during project/center-level discussions from time to time, often they are set aside as they require more in-depth analysis or discussion than can be applied at that level.

This section is therefore intended to make you aware and gather additional data on existing initiatives, gather thoughts for additional initiatives (through feedback forms on this topic - ensuring to annotate that is a new initiative or data or a comment), and solicit volunteers/participants across the RMA community. Feel free to reach out to points-of-contact directly.

Additional information on R&M initiatives from OSMA can be found here: [OSMA Reliability and Maintainability \(R&M\)](#) or provide feedback, comments, corrections via the [R&M Feedback Form](#) to enable the continued readiness and continuous relevance of the data provided within this site.

LEADS

- Tony DiVenti, R&M Technical Fellow
- Nancy J Lindsey, Deputy R&M Technical Fellow

LINKS

- OSMA
- CSFC RMA Assessment Branch
- HQ R&M
- KSC Reliability
- OSMA MBMA
- NASA SMA DT
- NEN
- S3V/SSRI
- SMA Tools



RMA: PoF Handbook on NASA RMA Knowledge Portal (<https://rmakp.nasa.gov/display/RMAKP/5.+Specialty+Topics#tabs-6>) and SharePoint (<https://nasa.sharepoint.com/teams/Reliability930/Shared%20Documents/Forms/AllItems.aspx?csf=1&web=1&e=yqhHiB&CID=cc906f35%2D98aa%2D46f7%2Db770%2D1afb8a5c99fa&FolderCTID=0x012000C152158E956F544CAF8CF887EDB162DE&id=%2Fteams%2FReliability930%2FShared%20Documents%2FRM%20Training%20Development%20Area%2FPhysics%20of%20Failure%20Handbook>)

SMA: Continue to share existence and solicit feedback/participation in the community of practice via conferences and discipline peers. Gather data/Case Studies

Engineering: Share on other virtual/collaboration platforms. Conduct research and synthesize experience data. Establish a formal Community of Practice or become a branch from another one like NSET? Or NESG? Gather data/Case Studies

NASA/NEPP: Share on other virtual/collaboration platforms. Maintain handbook as a formal NASA handbook. Add Methodology to STEP/SATERN. Conduct research and synthesize experience data. Gather data/Case Studies

Industry/Academia/Partners: Share with and gather data/Case Studies at Conferences.

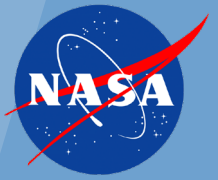
SharePoint: NASA Reliability and Maintainability (R&M) Technical Community

Documents > RM Training Development Area > Physics of Failure Handbook

Name	Modified	Modified By
Version 1 Comments and Case Study submissions	October 13, 2023	Fred Matthews, Cassini
Handbook Comment Materials	June 12, 2023	Lindsey, Nancy (NASA, Inc)
Paper-Presentation-R&M_2022_Infusing Big Data in PoF Framework...	January 25, 2022	Lindsey, Nancy (NASA, Inc)
PoF Overview REV A1 NSET 1-12-22 (Final) (1) (1) (1)	January 25, 2022	Lindsey, Nancy (NASA, Inc)
PoF Overview REV A1 NSET 1-12-22 (Final) (1) (1) (1)	January 25, 2022	Lindsey, Nancy (NASA, Inc)
PoF Handbook Overview REV (1) (1) (1)	November 29, 2021	Lindsey, Nancy (NASA, Inc)

We are counting on All of NASA and beyond to participate/ support continued research and data sharing!





Questions





Backup



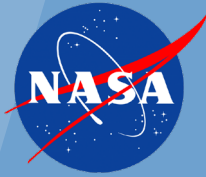


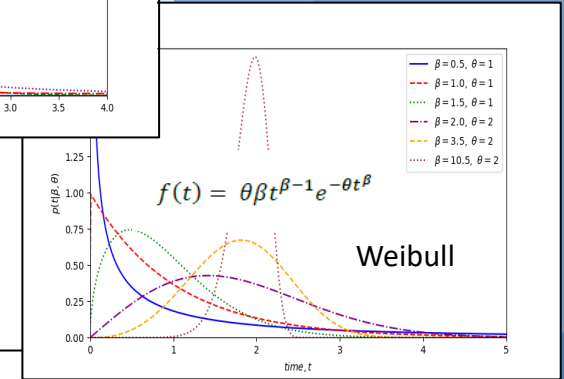
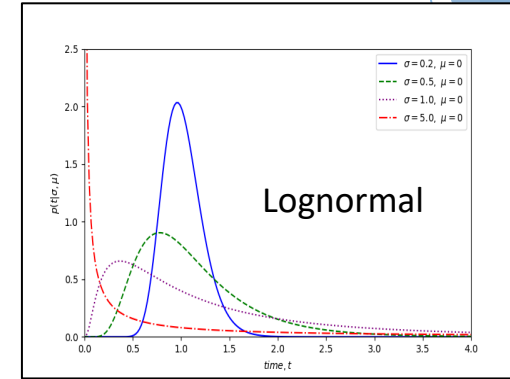
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Empirical: Analysis methods that study the failure history of parts under given conditions, then fits the failure data to a probability distribution. Responsive to new concepts.

Case Studies: NASA examples of application (separate and controllable); Ever increasing set – Community sourcing!

Empirical analysis uses operations and experimentation that exposes a system to multiple branches of physics (e.g., Thermodynamics, Kinematic/Static Mechanics, Acoustics, Fluids, Optics, Electrical) and the exhibited performance can be used to formulate the likelihood of failure of like systems under similar exposures using statistical approximations (e.g., Normal, Lognormal, Weibull, Thermal, Bayesian, Electromigration).



Thermal/Electrical

$$L_{med} = \left[\frac{A}{j^n} \right] \cdot \exp \left[-\frac{E^*}{k_B T} \right],$$

$$t_f = A(RH)^{-n} e^{\frac{Ea}{kT}}$$

Bayesian

$$\lambda_{Bayesian} = \frac{\delta'}{\rho'} = \frac{\delta + r}{\rho + T}$$

given $\rho = \frac{\delta}{E(\lambda)}$ and $\delta = \frac{1}{[cov(\lambda)]}$

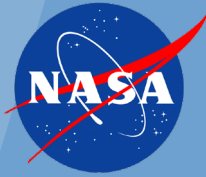


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Case Studies: NASA examples of application (separate and controllable); Ever increasing set – Community sourcing!

Deterministic analysis uses the theories of physics (e.g., Thermodynamics, Kinematic/Static Mechanics, Acoustics, Fluids, Optics, Electrical) to formulate the likelihood of failure based on hypothetical or non-use-case (accelerated performance) exposures. These analysis depend on detailed system models and an understanding of the phenomenon that contribute to eventual or sudden failure of a system to formulate a prediction.

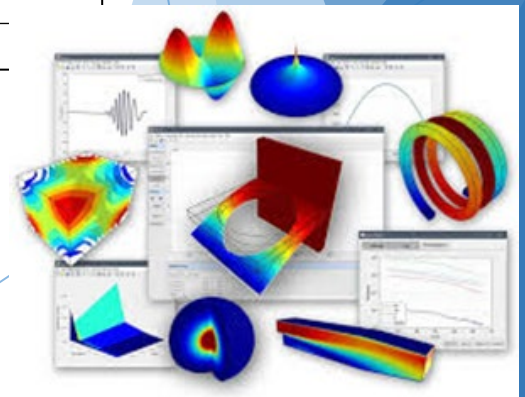
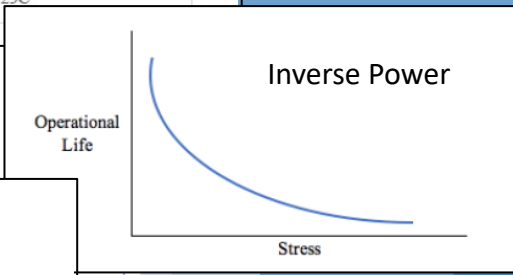
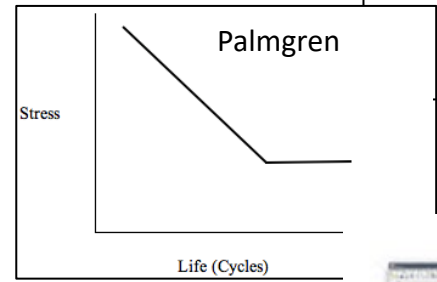
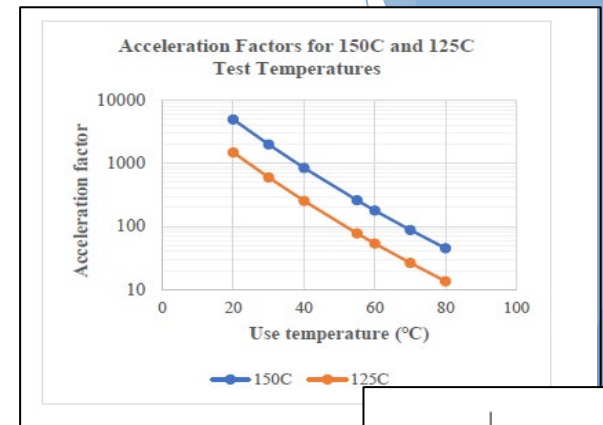




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Aggregation: Using a single method or multiple methods concurrently with or in lieu of reference rates (e.g., handbook data) to develop system failure likelihood using statistical techniques and considering dependencies of individual findings. Responsive to capability/concept advancement uncertainties, model-based, etc.

Case Studies: NASA examples of application (separate and controllable); Ever increasing set – Community sourcing!

Empirical and Deterministic analyses are not necessarily mutually exclusive and can either independently or in combination inform the final likelihood of failure assumed for a system. Considering this, it is important for the analyst to evaluate the magnitude, independence, and dependence of each likelihood given by each physics of failure methodology on a case-by-case basis, so that statistical techniques, such as Fault Trees, Bayesian Networks, or Conditional Probability can be applied once or multiple times until all likelihoods are combined or considered.

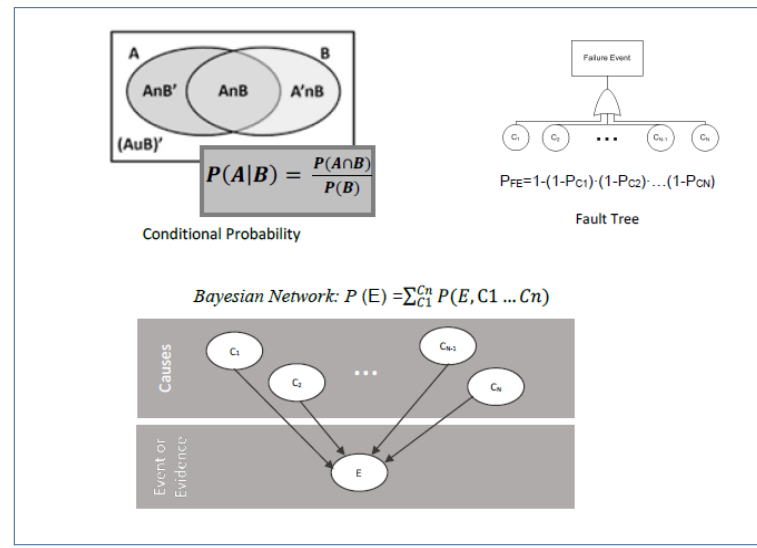
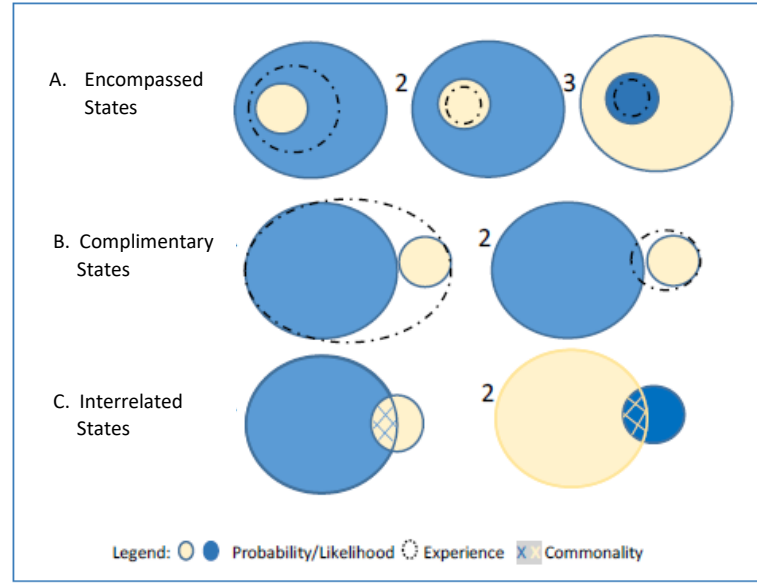




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Future: Technology advancement infusion of Multiphysics tools, Artificial Intelligence, and Machine Learning.

Case Studies: NASA examples of application (separate and controllable); Ever increasing set – Community sourcing!

Case Studies are included for clarity and as part of the living nature of the document:

- A General Reliability Model for Ni-BaTiO3-Based Multilayer Ceramic Capacitors
- Reliability Analysis of Aero-Equipment Components Life Based on Normal Distribution Model
- An Investigation of the Electrical Short Circuit Characteristics of Tin Whiskers
- GOES-T GSFC Magnetometer Reliability Model
- Analysis of Space Shuttle Flight Hardware Crack or Crack-Like Defect Data
- Bayesian Approach for Reliability Assessment of Sunshield Deployment on JWST
- Analysis and Life Testing for Design of Cryogenic Bearing Assemblies on the James Webb Space Telescope Optical Telescope Element
- Single-Event Transient Case Study for System Level Radiation Effects Analysis
- EOS Aqua Extended Mission Reliability Study Report, Revision C
- New Approach to Total Dose Specification for Spacecraft Electronics
- Improving Reliability of High-Power Quasi-CW Laser Diode Arrays Operating in Long Pulse Mode
- Damage Propagation Modeling for Aircraft Engine
- Degradation of Leakage Currents and Reliability Prediction for Tantalum Capacitors
- X-43A Rudder Spindle Fatigue Life Estimate and Testing
- A Thermal Runaway Failure Model for Low Voltage BME Ceramic Capacitors with Defects
- Analysis of Thermomechanical Fatigue of Unidirectional Titanium Metal Matrix Composites
- An Evaluation of Effects of Molding Compound Properties on the Reliability of Ag Wire Bonded Components
- Comparison of Experimental and Theoretical Thermal Fatigue Lives for Five Nickel Base Alloys
- Effect of High Temperature Storage in Vacuum, Air, and Humid Conditions on Degradation of Gold/Aluminum Wire Bonds in PEMs
- And More

Today we have Multiphysics tools (e.g., COMSOL, MATLAB, Windchill, Ansys Sherlock, Cadence, Altair, etc.) to assist in the assessment of failure likelihood but these have limitations.

Based on the ongoing research, in the future PoF modeling will likely include Artificial Intelligence and Machine Learning to enable a more complete evaluation with the application of predictive and statistical learning techniques.

For this to be possible research and data are needed from the community and must be shared with the community.



